

### **General Description**

The NTMFS4C027N use advanced SGT MOSFET technology to provide low RDS(ON), low gate charge, fast switching and excellent avalanche characteristics. This device is specially designed to get better ruggedness and suitable to use in

#### **General Features**

V<sub>DS</sub> =30V l<sub>D</sub> =60A

 $R_{DS(ON)} < 5.8m\Omega @ V_{GS}=10V$ 

## Applications

Consumer electronic power supply Motor control

Synchronous-rectification Isolated DC

Synchronous-rectification applications

#### Package Marking and Ordering Information

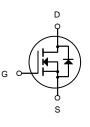
Product ID	Pack	Brand	Qty(PCS)
NTMFS4C027N	DFN5X6-8L	HXY MOSFET	5000

#### Absolute Maximum Ratings (Tc=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
Vds	Drain-Source Voltage	V	
Vgs	Gate-Source Voltage	±20	V
I₀@Tc=25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	60	А
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	38	А
Ідм	Pulsed Drain Current <sup>2</sup>	135	А
EAS	Single Pulse Avalanche Energy <sup>3</sup>	29.8	mJ
P₀@Tc=25°C	Total Power Dissipation <sup>4</sup>	30	W
Тѕтс	Storage Temperature Range -55 to 150		°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R <sub>θ</sub> JC	Thermal Resistance from Junction-to-Ambient <sup>3</sup> 4.6		°C/W
R <sub>0</sub> JA	Thermal Resistance Junction-Ambient <sup>1</sup>	50	°C/W







N-Channel MOSFET



Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30			V
Rds(on)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =20A		4.4	5.8	mΩ
		V <sub>GS</sub> =4.5V , I <sub>D</sub> =15A		6.9	9	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.2		2.5	V
	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25℃			1	uA
IDSS		V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55℃			5	
Igss	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =20A		67		S
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		1.7		Ω
Qg	Total Gate Charge (4.5V)			8		
Qgs	Gate-Source Charge	V <sub>DS</sub> =15V , V <sub>GS</sub> =4.5V , I <sub>D</sub> =15A		2.4		nC
Q <sub>gd</sub>	Gate-Drain Charge			3.2		
T <sub>d(on)</sub>	Turn-On Delay Time			7.1		
Tr	Rise Time	$V_{DD}$ =15V , $V_{GS}$ =10V , $R_G$ =3.3 $\Omega$		40		ns
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =15A		15		
T <sub>f</sub>	Fall Time			6		
Ciss	Input Capacitance			814		
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		498		pF
Crss	Reverse Transfer Capacitance			41		
ls	Continuous Source Current <sup>1,6</sup>	$V_G=V_D=0V$ , Force Current			60	А
$V_{\text{SD}}$	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25℃			1	V
trr	Reverse Recovery Time	IF=20A , di/dt=100A/μs ,		15		nS
Qrr	Reverse Recovery Charge			25		nC

## Electrical Characteristics (T<sub>J</sub> = 25°C, unless otherwise noted)

Note :

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

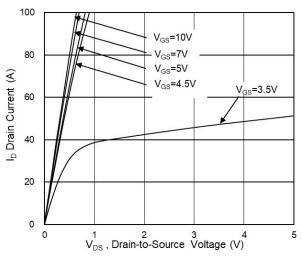
2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%

3. The EAS data shows Max. rating . The test condition is  $V_{\text{DD}}\text{=}25V, V_{\text{GS}}\text{=}10V, L\text{=}0.1\text{mH}, I_{\text{AS}}\text{=}24\text{A}$ 

4. The power dissipation is limited by 150°C junction temperature 5. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



# **Typical Characteristics**



**Fig.1 Typical Output Characteristics** 

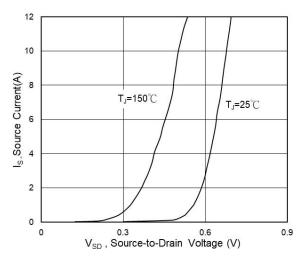
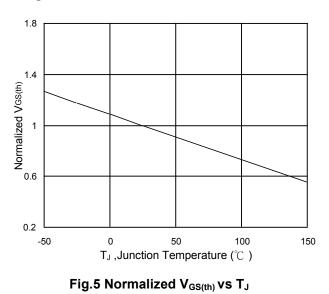


Fig.3 Source Drain Forward Characteristics



12 10 CB CB CB CGB CGB

Fig.2 On-Resistance vs G-S Voltage

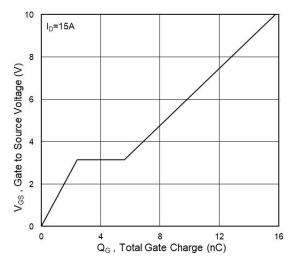
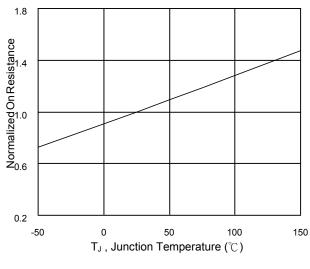
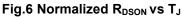
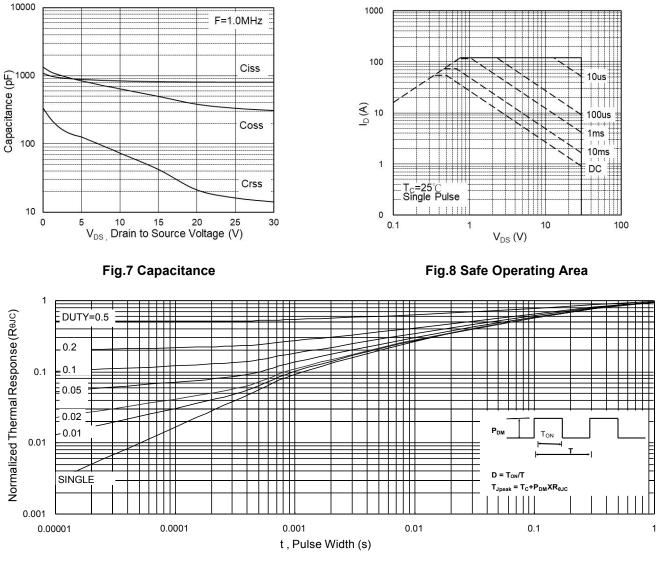


Fig.4 Gate-Charge Characteristics











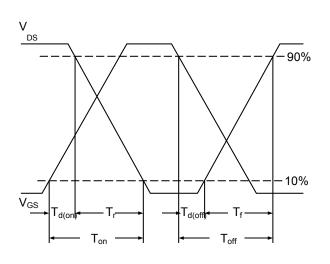


Fig.10 Switching Time Waveform

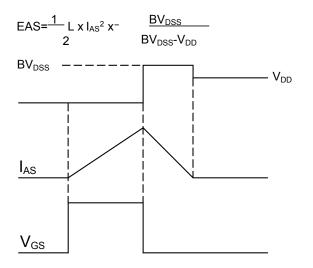
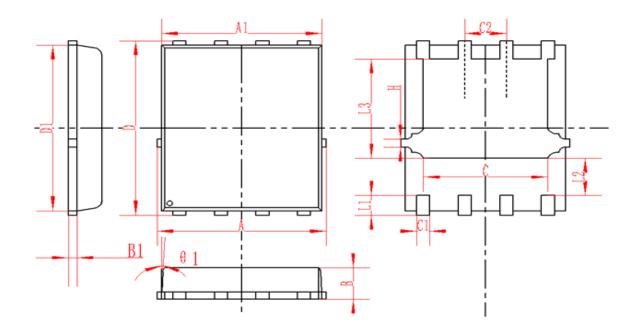


Fig.11 Unclamped Inductive Switching Waveform



# DFN5X6-8L Package Information



SYMBOL	MM		INCH				
	MIN	NOM	MAX	MIN	NOM	MAX	
А	4.95	5	5.05	0.195	0.197	0.199	
A1	4.82	4.9	4.98	0.190	0.193	0.196	
D	5.98	6	6.02	0.235	0.236	0.237	
D1	5.67	5.75	5.83	0.223	0.226	0.230	
В	0.9	0.95	1	0.035	0.037	0.039	
B1	0.254REF		0.010REF				
С	3.95	4	4.05	0.156	0.157	0.159	
C1	0.35	0.4	0.45	0.014	0.016	0.018	
C2		1.27TYP			0.5TYP		
θ1	8°	10°	12°	8°	10°	12°	
L1	0.63	0.64	0.65	0.025	0.025	0.026	
L2	1.2	1.3	1.4	0.047	0.051	0.055	
L3	3.415	3.42	3.425	0.134	0.135	0.135	
Н	0.24	0.25	0.26	0.009	0.010	0.010	



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